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Technology

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# Notes about the limits of ultra-high speed solid-state imagers

**Dr Renato Turchetta**

STFC - Rutherford Appleton Laboratory (RAL)

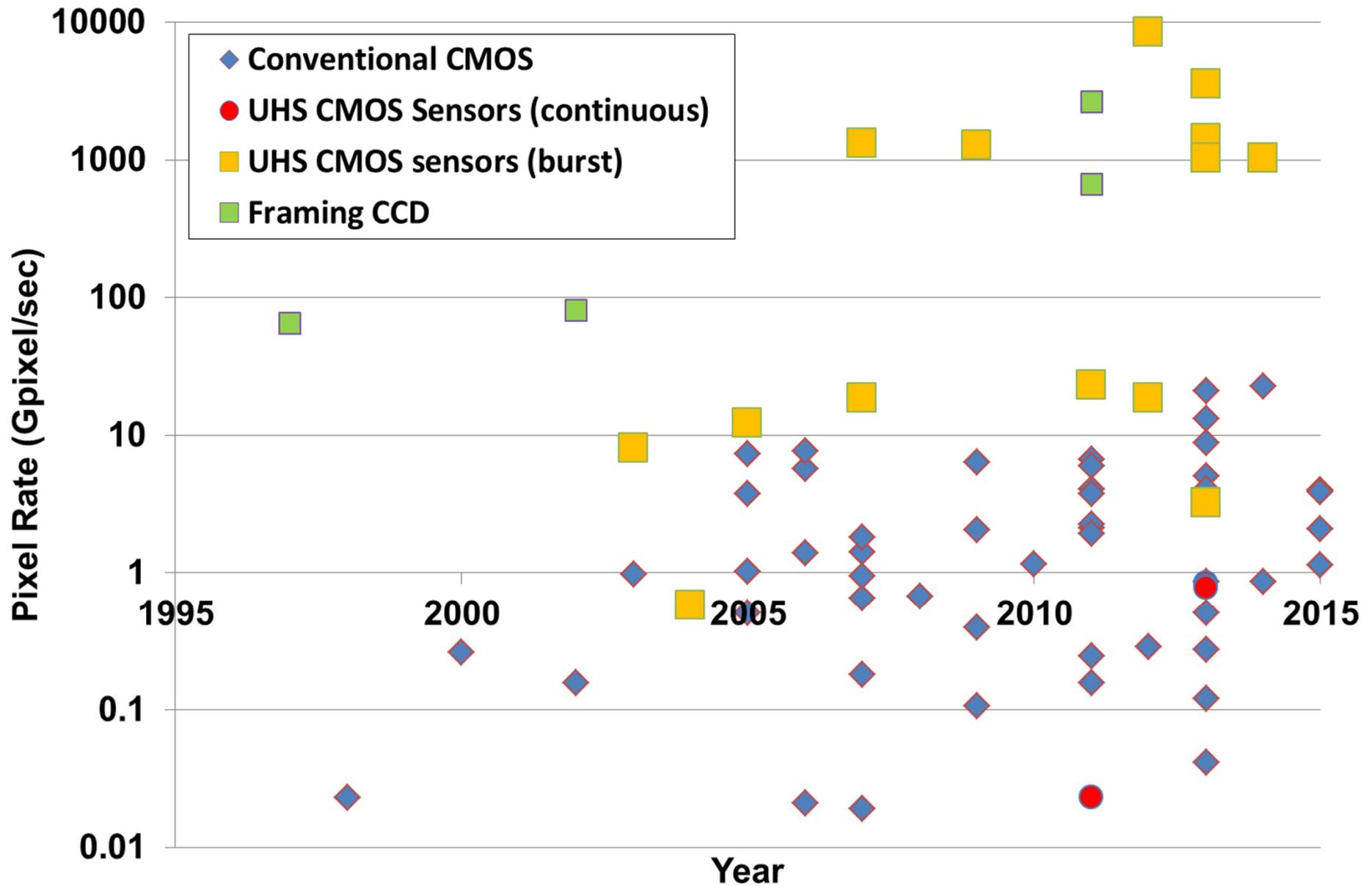
Oxfordshire, UK

E-mail: [renato.turchetta@stfc.ac.uk](mailto:renato.turchetta@stfc.ac.uk)





- **Current signal at high-speed →  
the Shockley-Ramo's theorem**
- **Dead time limit for photon  
counting devices**





**10s of Mega frames per second already  
available**

**Going towards Giga frames per second**

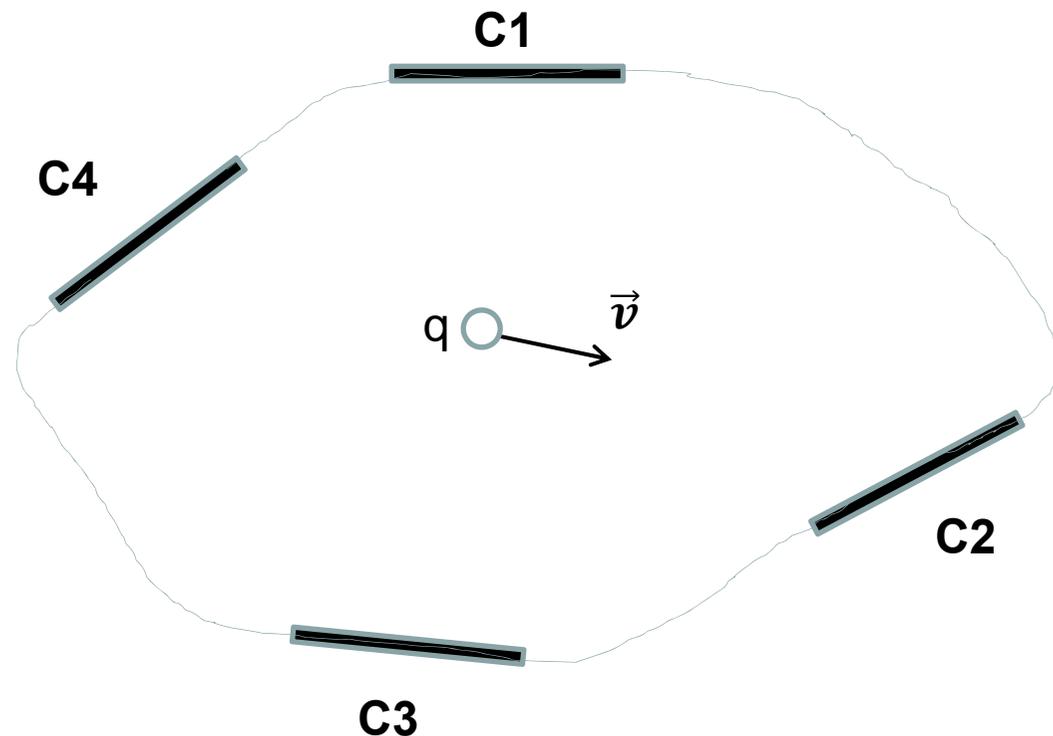
**Carrier transit time comparable with sampling  
time**

**How do we calculate the charge signal?**



Transit time of  
electrons comparable  
with frequency  
response of tubes.

What is the signal on  
the  $k$ -th electrode due  
to the movement of a  
carrier with charge  $q$ ?





# Shockley-Ramo's theorem

Current  $i(t)$  on one electrode due to a charge  $q$  moving with speed  $v(t)$  at point  $x$

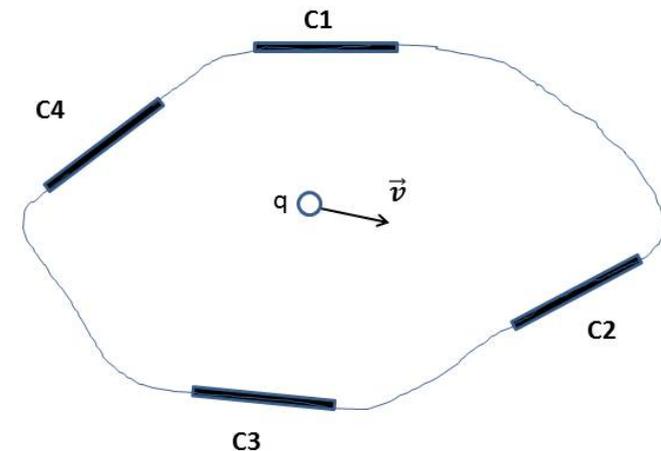
$$i_k(t) = q \vec{v} \cdot \vec{E}_W$$

$E_w(x)$  is the electric field obtained by setting the selected electrode at unit potential, all other electrodes at zero potential.

(Shockley 1938, Ramo 1939)

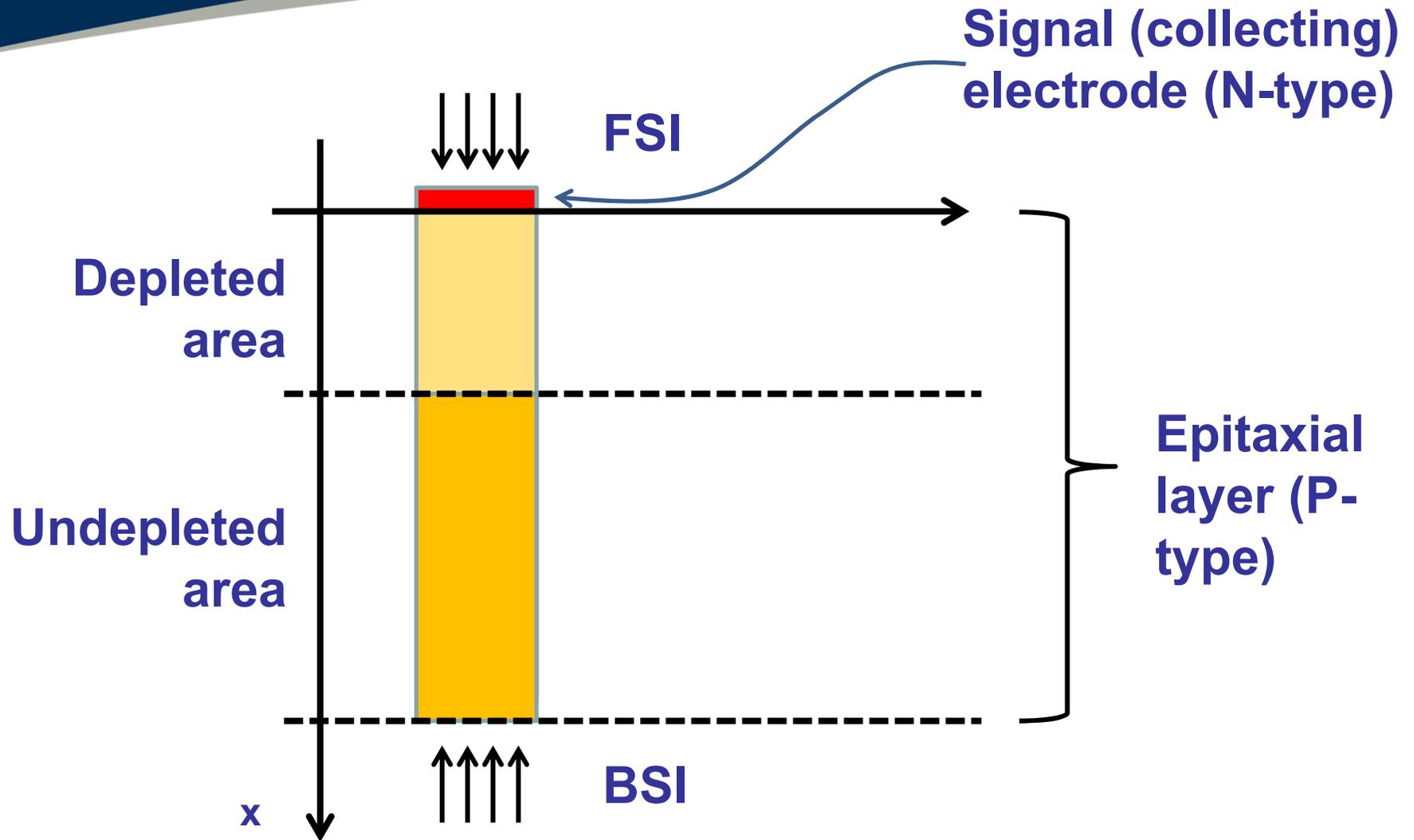
$E_w(x)$  calculated after removing all space charge .

(Cavalleri et al. 1971)





- **The current signal is induced by the movement of charge**
- **In semiconductor there are two types of carriers, electrons and holes, hence two current components**
- **The two components are summed to give the total current**
- **The integral of the total (sum) current is equal to the collected charge**



$$E_0(x) = 1/w$$

2000 e-h pair generated



Epi  $w = 5 \mu\text{m}$

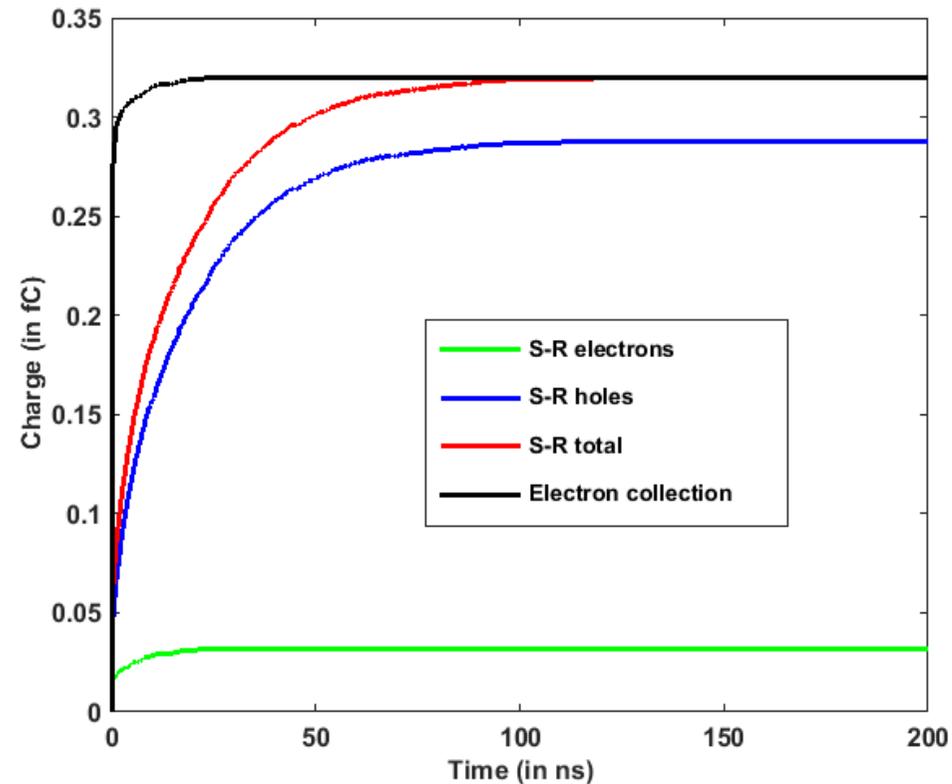
$N_D = 10^{18} \text{ cm}^{-3}$

$N_A = 2 \cdot 10^{15} \text{ cm}^{-3}$

$V_{\text{bias}} = 1.5\text{V}$

FSI

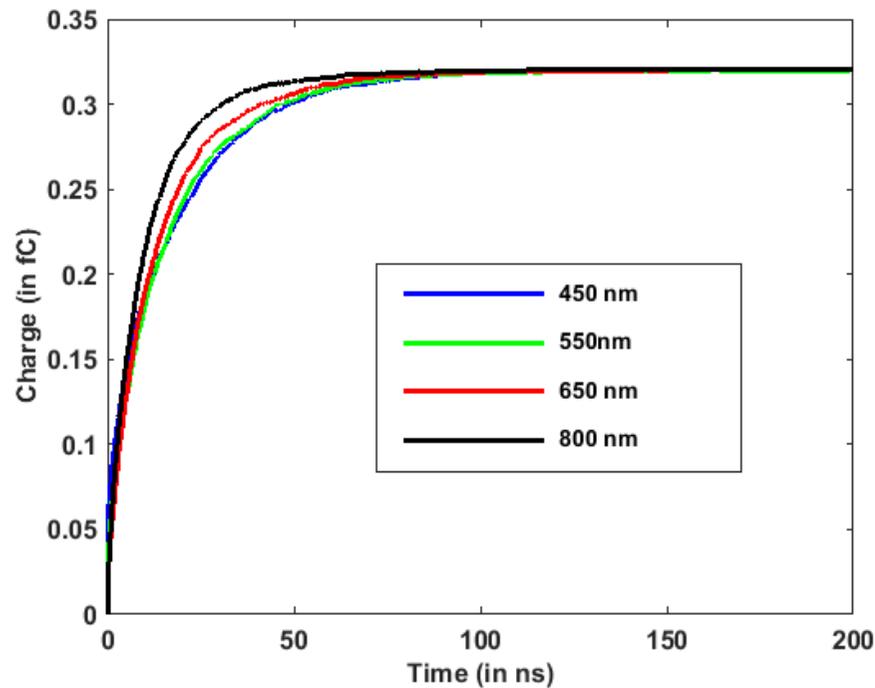
w.l. = 450 nm



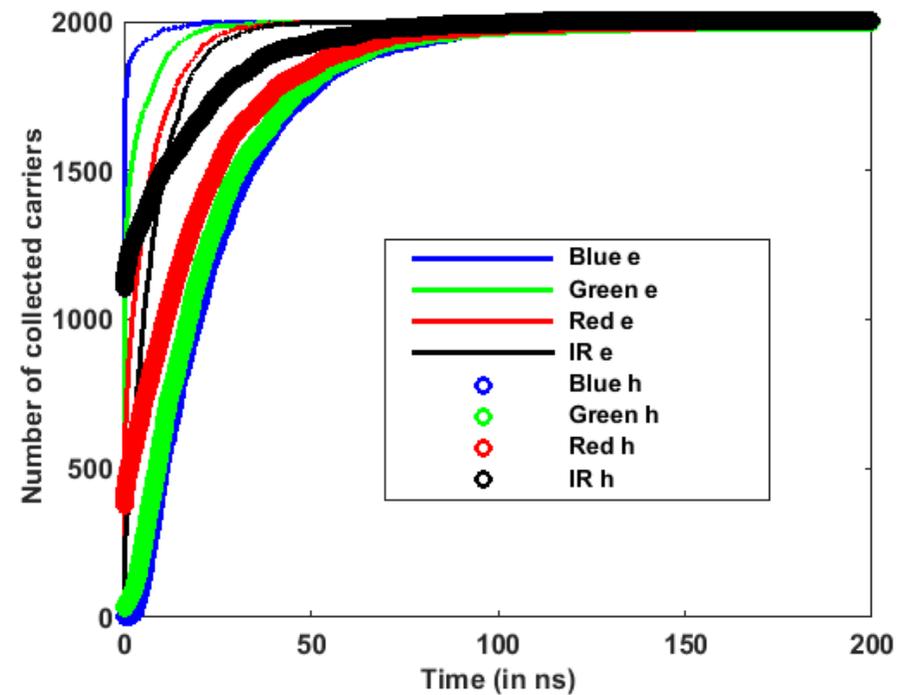
**Ramo-Shockley gives a very different result!**



## Ramo-Shockley



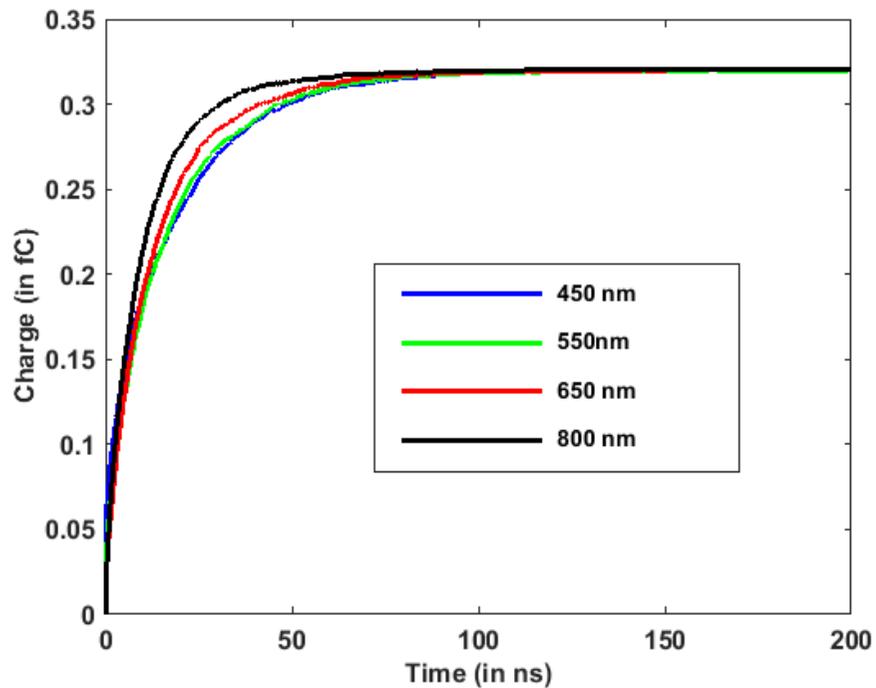
## Carrier collection



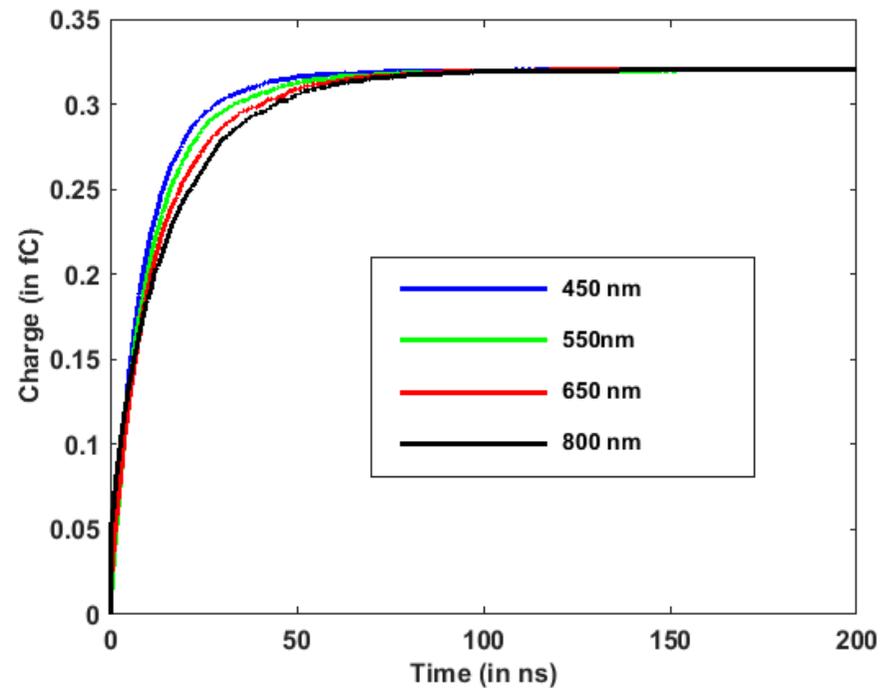
**Thin epi. Low resistivity.**



## FSI



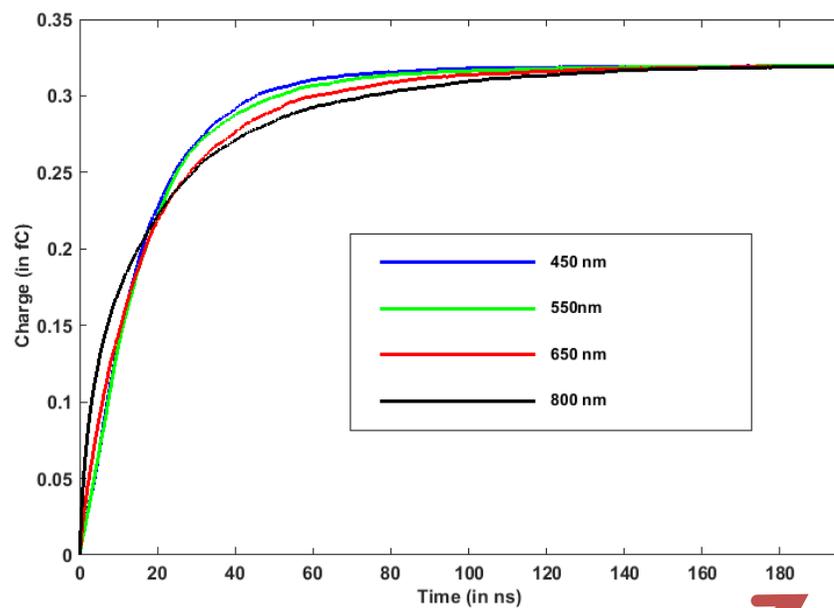
## BSI



**Thin epi. Low resistivity.**

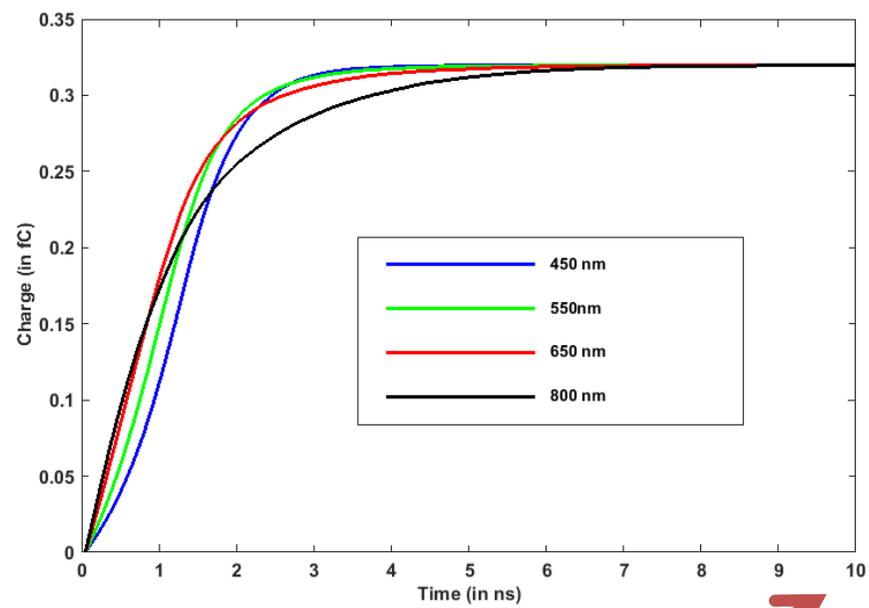


$$V_{\text{bias}} = 1.5\text{V}$$



200 ns

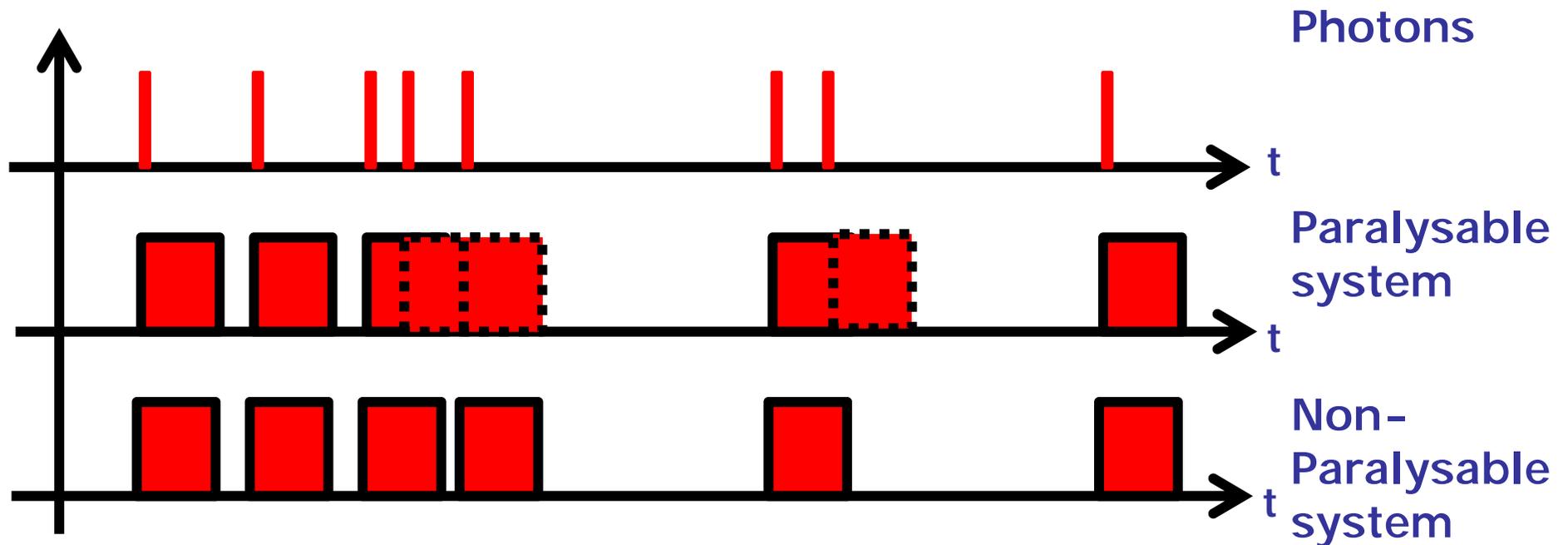
$$V_{\text{bias}} = 5\text{V}$$



10 ns



Deadtime in counting systems. Basic models: paralyzable and non-paralyzable





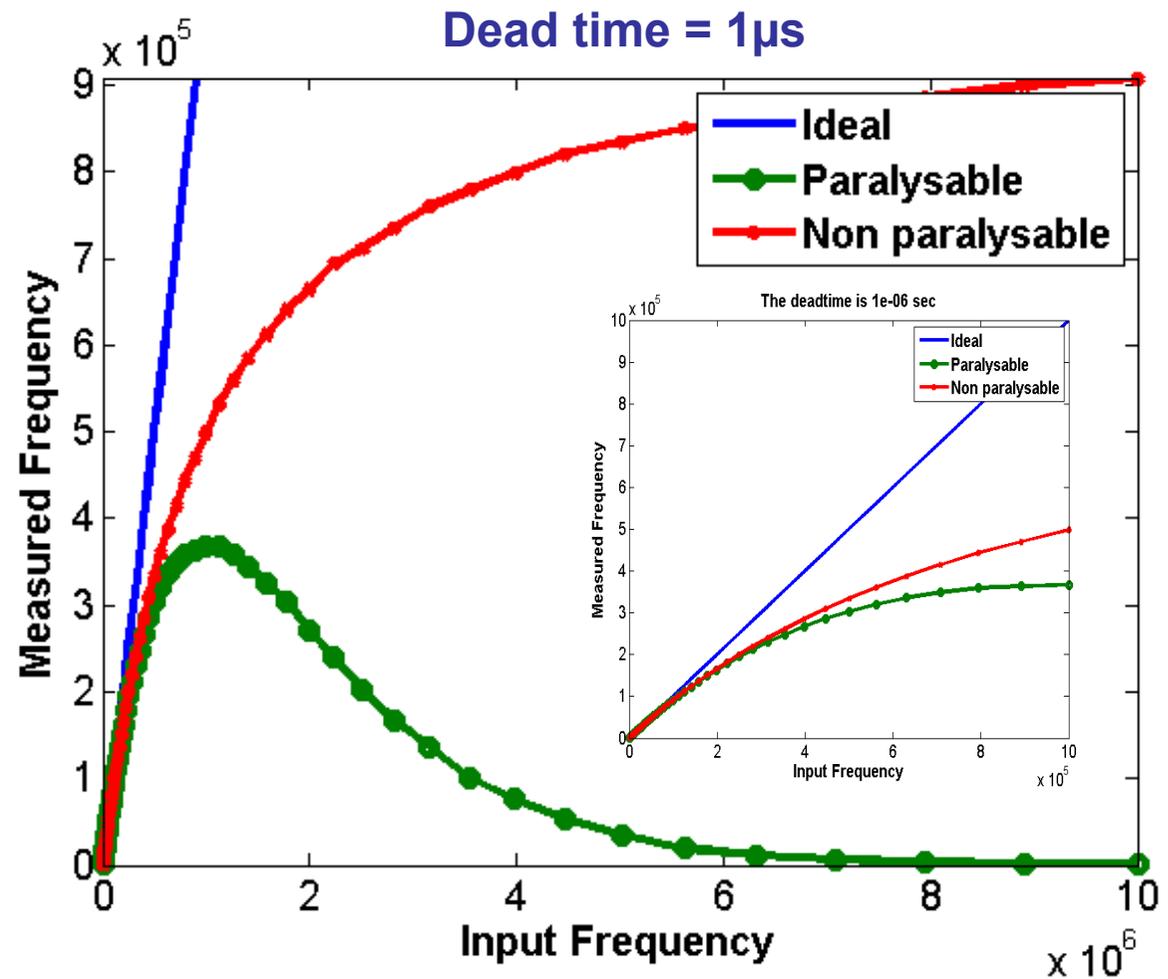
Maximum  
count rate set  
by dead time

Frame rate  $\uparrow\downarrow$

Maximum

count  $\downarrow\downarrow$

Bit depth





- **Shockley-Ramo's theorem → current induced by the movement of charge**
- **Careful design to avoid temporal colour cross-talk at ultra-high speed**
- **Dead time to set trade-offs between amplitude and time resolution for photon counting sensors**